

Title (en)

MASS ANALYSIS DEVICE WITH WIDE ANGULAR ACCEPTANCE INCLUDING A REFLECTRON

Title (de)

MASSENANALYSEEINRICHTUNG MIT GROSSER WINKELANNAHMEFÄHIGKEIT MIT EINEM REFLEKTRON

Title (fr)

DISPOSITIF D'ANALYSE DE MASSE A LARGE ACCEPTANCE ANGULAIRE COMPRENANT UN REFLECTRON

Publication

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Application

EP 10703478 A 20100212

Priority

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Abstract (en)

[origin: WO2010092141A1] The invention relates to a mass analysis device (100) with wide angular acceptance, in particular such as a mass spectrometer or an atom probe microscope, including a means for receiving a sample (101), a means for extracting ions from the surface of the sample (101), and a reflectron (103) producing a toroidal electrostatic field in which the equipotential lines are defined by a first curvature in a first direction and a first centre of curvature (105), and a second curvature in a second direction perpendicular to the first direction and a second centre of curvature, characterised in that the sample (101) is placed adjacent to the first centre of curvature (105).

IPC 8 full level

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